Nuutti Hyvönen: *Diffusive tomography methods: Special boundary conditions and characterization of inclusions*; Helsinki University of Technology Institute of Mathematics Research Reports A471 (2004).

Abstract: *This thesis presents mathematical analysis of optical and electrical impedance tomography. We introduce papers* [I–III]*, which study these diffusive tomography methods in the situation where the examined object is contaminated with inclusions that have physical properties differing from the background.*

AMS subject classifications: 35R30, 35Q60, 35J25, 31A25, 31B20, 35R05, 78A70

Keywords: inverse boundary value problems, variational principles, optical tomography, non-scattering regions, radiative transfer equation, diffusion approximation, electrical impedance tomography, inverse conductivity problem, electrode models, inclusions, factorization method

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ISBN 951-22-7068-4
ISSN 0784-3143

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